TECHNICAL MANUAL

ORGANIZATIONAL MAINTENANCE MANUAL
ELECTRONIC CIRCUIT PLUG-IN
UNIT TEST SET TS-3317 EQUIPMENT MAINTENANCE

EXPANDED TROUBLESHOOTING
(LOGIC DIAGRAMS)

GUIDED MISSILE AIR DEFENSE SYSTEM
AN/TSQ-73

HEADQUARTERS, DEPARTMENT OF THE ARMY

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ORGANIZATION MAINTENANCE MANUAL: ELECTRONIC CIRCUIT PLUG-IN UNIT TEST SET TS-3317

GUIDED MISSILE AIR DEFENSE SYSTEM AN/TSQ-73

REPORTING ERRORS AND RECOMMENDING IMPROVEMENTS

You can help improve this publication. If you find any mistakes, or if you know of a way to improve the procedures, please let us know. Mail your Letter, DA Form 2028 (Recommended Changes to Publications and Blank Forms), or DA Form 2028-2 located in back of this manual direct to: Commander, U.S. Army Missile Command, ATTN: DRSMI-SNPM, Redstone Arsenal, AL 35898. A reply will be furnished to you.

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HAGN60V	23
HARM20V	14-2
HBRM10V	14-2
HBYBP0V	4
HAFBAAV	22
HBCI0B1	2
HBCI1B1	2
HBCI2B1	2
HBCI3B1	2
HBCI4B1	2
HBCI5B1	2

OUTPUT	FO-SH
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HBKB15V1	5
HBKB16V1	5
HBKB17V1	5
HBKB18V1	5
HBK010V	12-1
HBK020V	12-1
HBK030V	12-1
HBK040V	12-3
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HAECM0V	6-2, 6-3, 6-4
HAMGC3T	6-1, 6-3, 6-4
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HA6CC0V	6-1, 6-2, 6-3, 6-4
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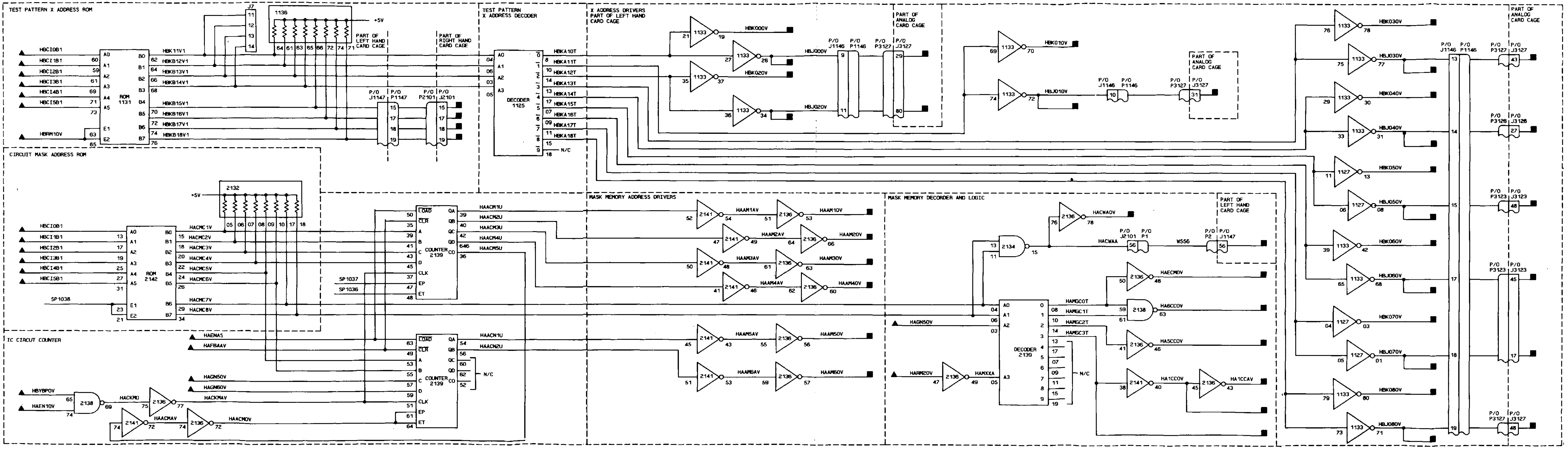
HACWA0V	19



NOTES: UNLESS OTHERWISE SPECIFIED

1. PARTIAL REFERENCE DESIGNATIONS ARE SHOWN; FOR COMPLETE DESIGNATIONS, PREFIX WITH APPLICABLE UNIT NUMBER AND ASSEMBLY DESIGNATOR.
2. DEFINITIONS FOR SYMBOLS SHOWN ARE AS FOLLOWS:
   - ▲ INPUT FROM ANOTHER FIGURE
   - △ INPUT FROM SAME FIGURE
   - ■ OUTPUT TO ANOTHER FIGURE
   - ☑ OUTPUT TO BOTH SAME AND ANOTHER FIGURE
   - ☐ OUTPUT TO SAME FIGURE
3. REFER TO TABLES 7-4, 7-5, AND 7-6 FOR CIRCUIT CARD LOCATIONS.
4. REFER TO TABLES 7-7, 7-8, AND 7-9 FOR CIRCUIT CARD TEST POINTS.
5. REFER TO POWER DISTRIBUTION FOR DC POWER AND GROUND CIRCUITS.
6. CIRCUIT SYMBOLS INCLUDE CARD LOCATION AND CIRCUIT PIN NUMBERS.

MS 428179

FO-3. Circuit Mask Memory Control Logic Diagram

FO-3. Circuit Mask Memory Control Logic Diagram